

DESCRIPTION:

With high ability to withstand the shock loading of large current, **VSA06/VSB06** triacs provide high dv/dt rate with strong resistance to electromagnetic interface. With high commutation performances, the products especially recommended for use on inductive load.



MAIN FEATURES

Symbol	Value	Unit
I _{T(RMS)}	6	Α
V _{DRM} /V _{RRM}	600/800	V



ABSOLUTE MAXIMUM RATINGS

Parameter			Symbol	Value	Unit
Storage junction temperature range		T _{stg}	-40 - 150	$^{\circ}\!\mathbb{C}$	
Operating junction temperature range			Tj	-40 - 125	$^{\circ}$
Repetitive peak off-state voltage (T _j =25℃)			V _{DRM}	600/800	V
Repetitive peak reverse voltage (T _j =25°C)		V _{RRM}	600/800	V	
RMS on-state current	TO-220A(Ins)/ TO-220F(Ins)/ TO-251 (Tc=100°C) TO-220B(Non-Ins) (Tc=105°C)		I _{T(RMS)}	6	Α
Non repetitive surge peak on-state current (full cycle, F=50Hz)			ITSM	60	Α
I ² t value for fusing (tp=10ms)			l ² t	18	A ² s
Critical rate of rise of on-state		dl/dt	50	A/µs	
current (I _G =2×I _{GT})		IV	ui/ut	10	Λίμο

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Peak gate current	I _{GM}	2	Α
Average gate power dissipation	P _{G(AV)}	1	W
Peak gate power	Р _{GМ}	5	W

ELECTRICAL CHARACTERISTICS (T_j =25 $^{\circ}$ C unless otherwise specified)

Symbol	Test Condition	Quadrant		Va	lue	Unit
				С	В	
lgт	V _D =12V R _L =30Ω	I - II -III	MAX	25	50	mA
		IV		50	70	
V _{GT}		ALL	MAX	1.5		V
V _{GD}	$V_D = V_{DRM} T_j = 125 °C$ R _L = 3.3KΩ	ALL	MIN	0.2		V
I _L I _G =1.2I _{GT}	1 -4 01	I -III-IV	MAX	50	70	mA
	IG = I.ZIGT	II	IVIAX	60	80	IIIA
lн	I _{TM} =0.2A		MAX	40	60	mA
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	200	500	V/µs

STATIC CHARACTERISTICS

Symbol	Parameter		Value(MAX)	Unit
V _{TM}	I _{тм} =8.5A tp=380µs	Tj=25℃	1.5	V
IDRM	V _D =V _{DRM} V _R =V _{RRM}	Tj=25℃	5	μA
I _{RRM}		Tj=125℃	1	mA

THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
R _{th(j-c)} junction to case(AC)		TO-220A(Ins) TO-220F(Ins)	2.9	
	TO-220B(Non-Ins)	2.3	°C/W	
		TO-251	2.7	

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FIG.1: Maximum power dissipation versus RMS on-state current

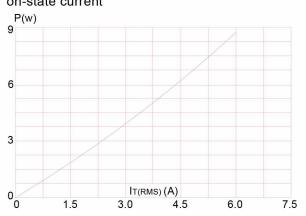


FIG.3: Surge peak on-state current versus number of cycles

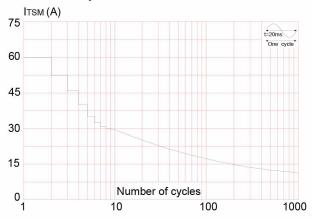


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of I^2t ($I - II - III : dI/dt < 50A/\mu s$; $IV : dI/dt < 10A/\mu s$)

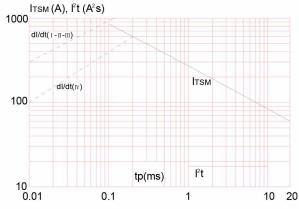


FIG.2: RMS on-state current versus case temperature

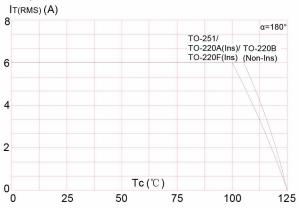


FIG.4: On-state characteristics (maximum values)

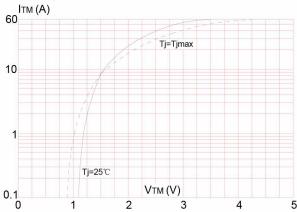


FIG.6: Relative variations of gate trigger current versus junction temperature

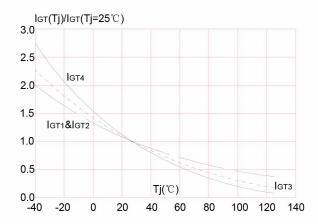




FIG.7: Relative variations of holding current versus junction temperature

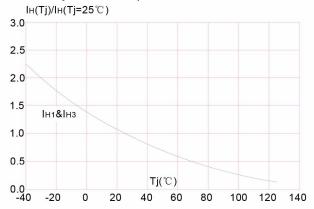


FIG.8: Relative variations of latching current versus junction temperature

